

Sulfur compounds

Application Note

Energy & Fuels

Authors

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Introduction

Analysis of trace sulfur compounds using selective detection is straightforward with Agilent CP-SilicaPLOT GC columns.



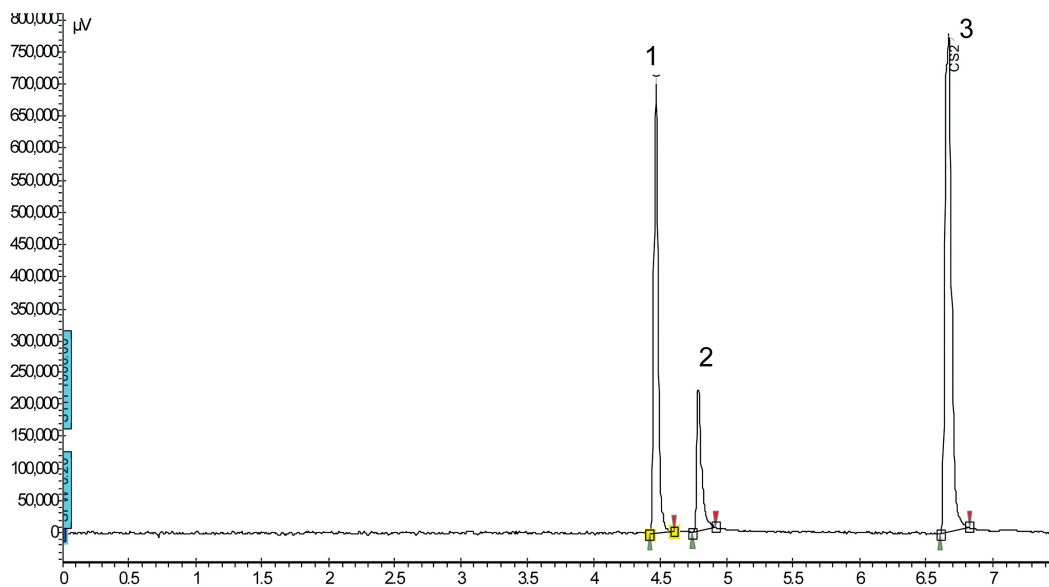
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Conditions

Technique : GC-capillary
Column : Agilent CP-SilicaPLOT, 0.53 mm x 30 m fused silica
(df = 6 μ m) (Part no. CP8570)
Temperature : 40 °C (2 min) \rightarrow 200 °C, 20 °C/min
Carrier Gas : He, 5 mL/min
Injector : Split, 1:10, T : 200 °C
InjectionVolume : 1 mL
Detector : PFPD, T : 200 °C
Sample : 5 - 20 ppm in nitrogen

Peak identification

1. COS 10 ppm,
2. H₂S 5 ppm,
3. CS₂ 20 ppm



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This information is subject to change without notice.

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